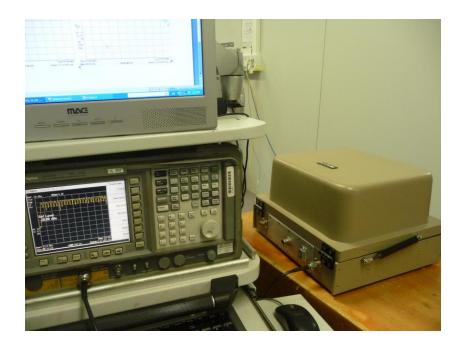


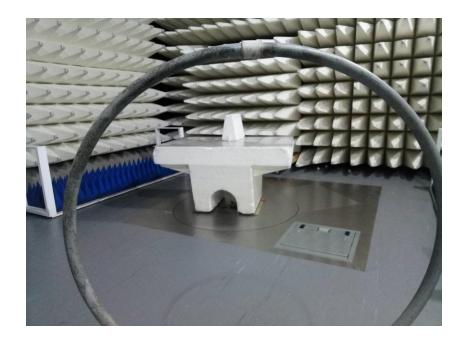
## Photograph No.1 Setup for OBW measurements



## Photograph No.2 Setup for band edge emission and hopping parameters measurements



Photograph No.3 Setup for spurious field strength measurements in anechoic chamber from 9 kHz to 30 MHz



Photograph No.4 Setup for carrier and spurious emissions measurements in anechoic chamber from 30 MHz to 1 GHz



Photograph No.5 Setup for field strength measurements in anechoic chamber above 1 GHz



## Photograph No.6 Setup for carrier field strength measurements, EUT cabling

